

Notice of References Cited	Application/Control No. 10/761,361		Applicant(s)/Patent Under Reexamination OGAWA ET AL.	
	Examiner TAN X. DINH		Art Unit 2627	Page 1 of 1

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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*	C	US-7,123,557 B2	10-2006	Heemskerk et al.	369/47.19
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NON-PATENT DOCUMENTS

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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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